Special Issue

Deep Learning-Based Smart Farm Techniques

Message from the Guest Editors

This Special Issue aims to cover recent advances in the development and application of deep learning techniques for smart farm applications. Topics of interest include, but are not limited to, the following

- Sensor techniques for deep learning-based smart farming
- Transmission techniques for deep learning-based smart farming
- Analysis techniques for deep learning-based smart farming
- Low-cost techniques for deep learning-based smart farming
- Edge computing techniques for deep learning-based smart farming
- Cloud computing techniques for deep learning-based smart farming
- Big data and IoT techniques for deep learning-based smart farming
- Deep learning-based applications of food-based farming
- Deep learning-based applications of livestock (cow, pig, and broiler chicken) farming

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

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